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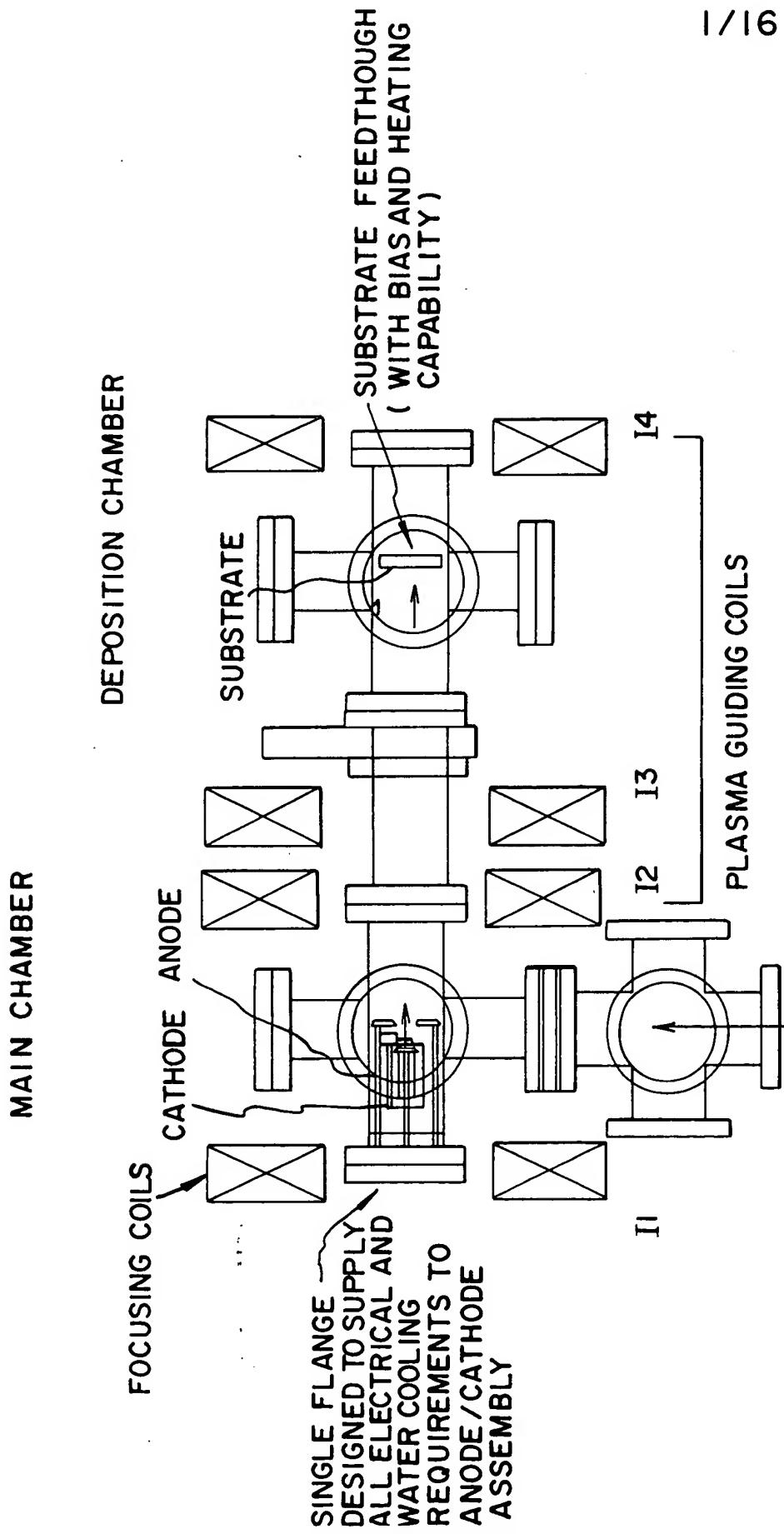


Fig. 1



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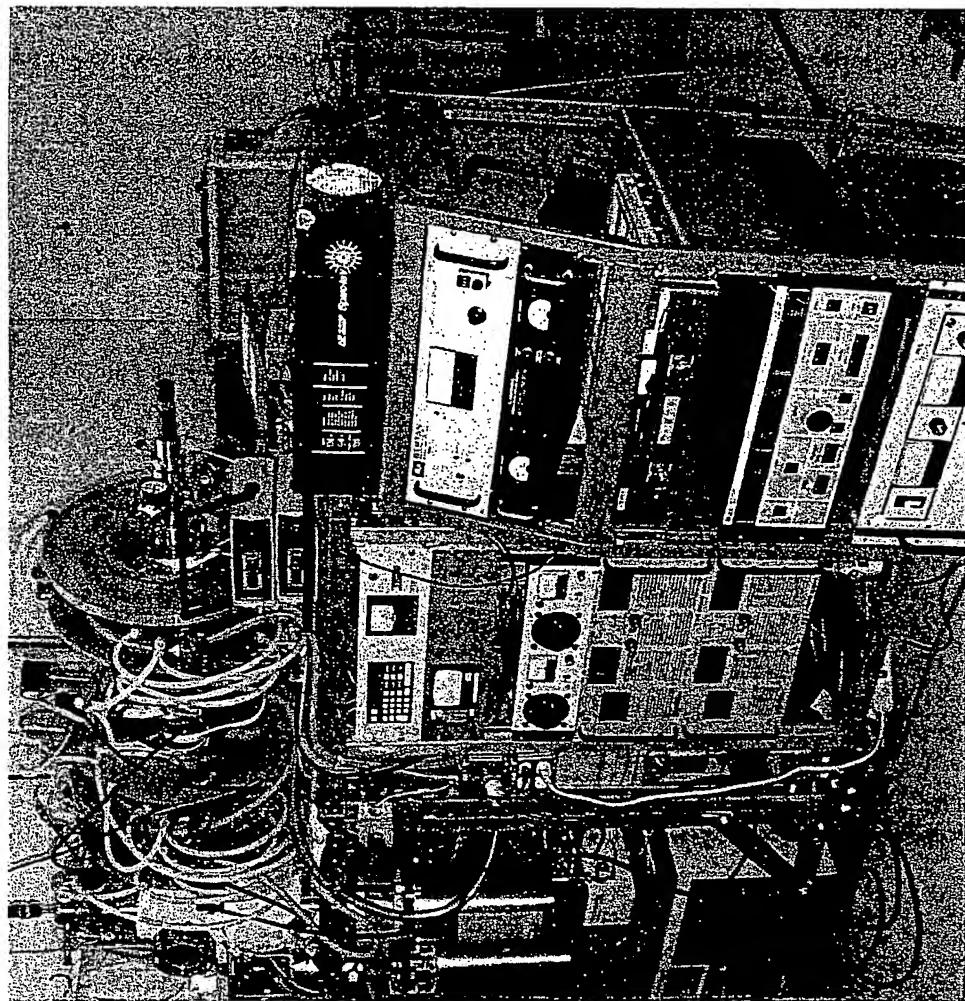
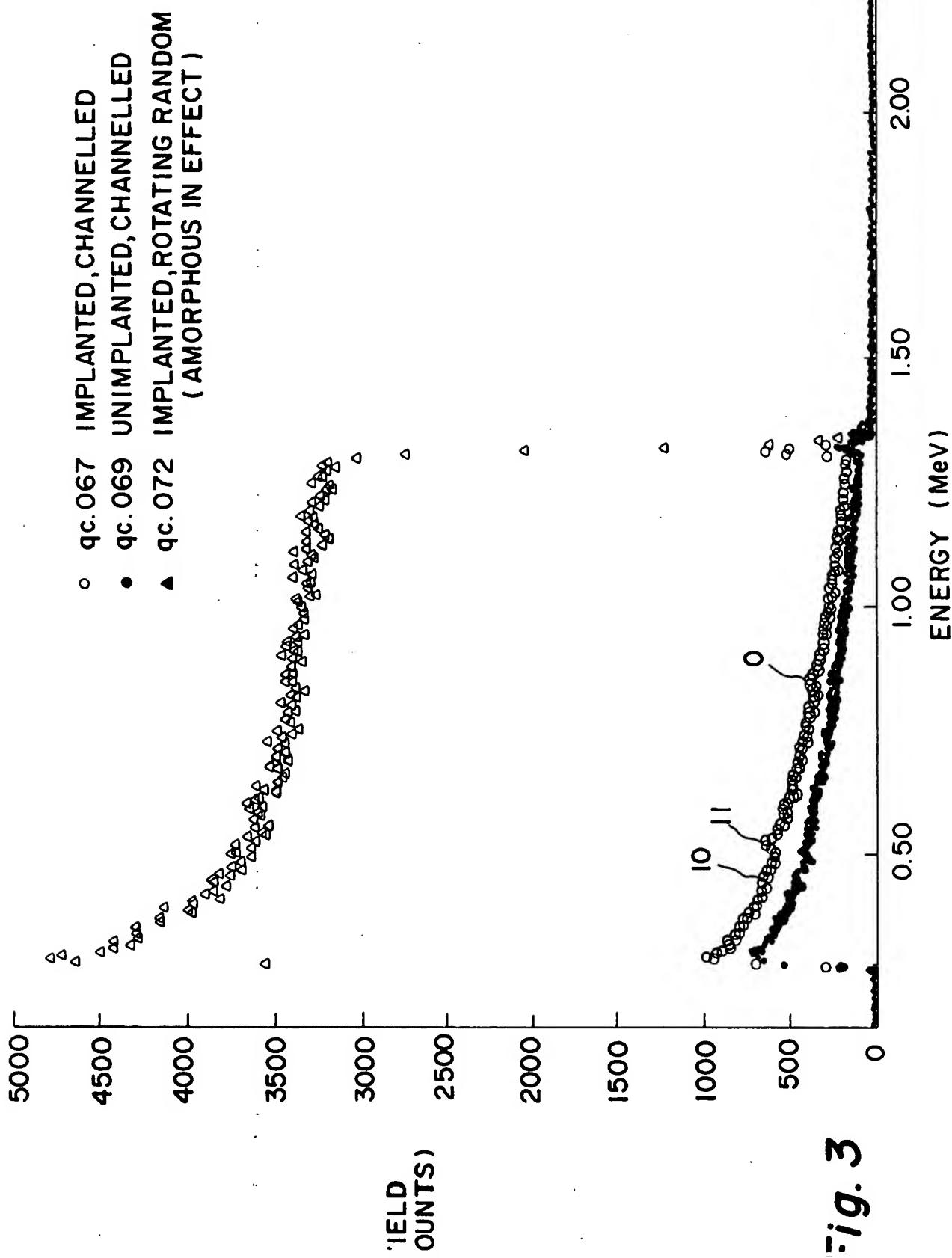


Fig. 2



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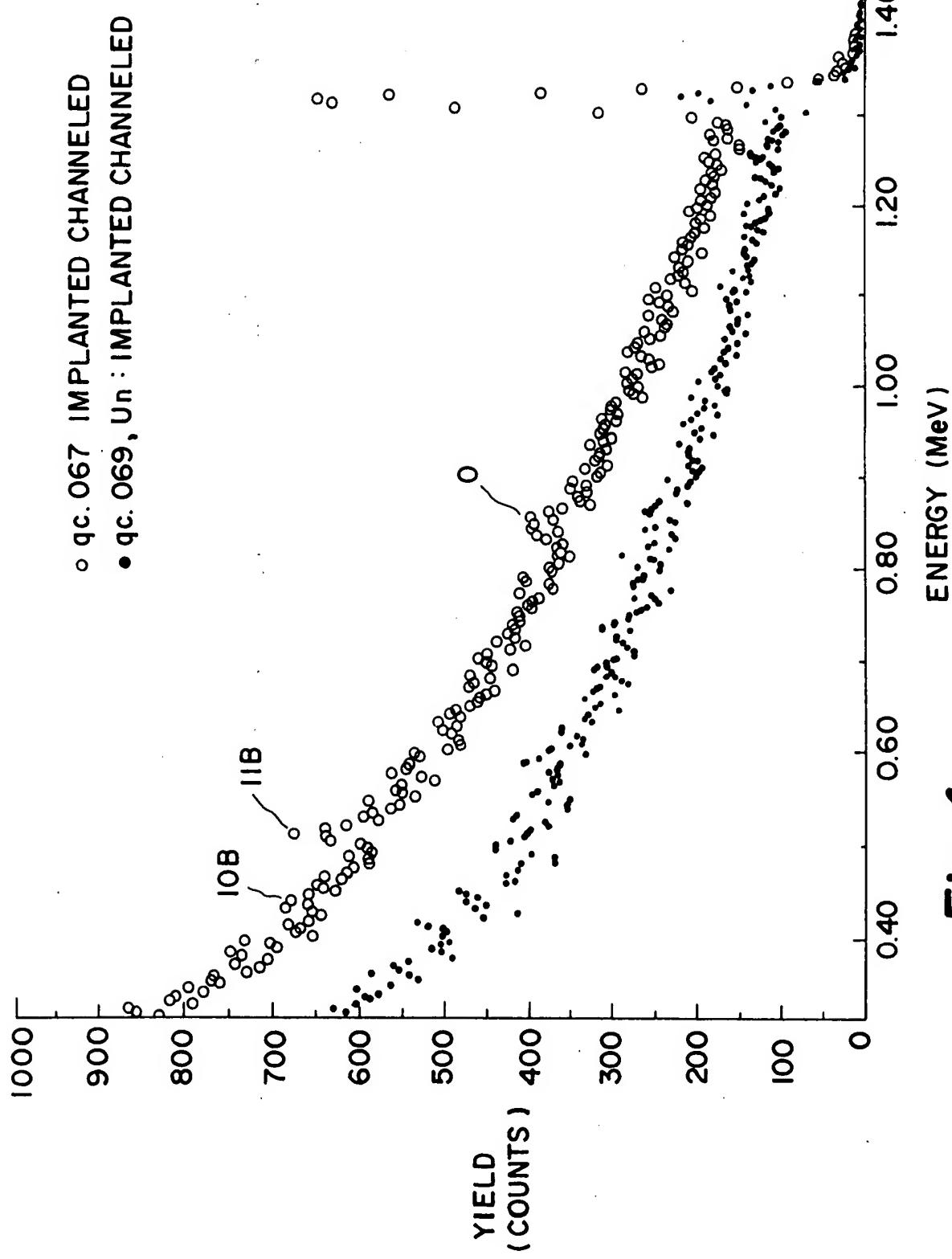


Fig. 4



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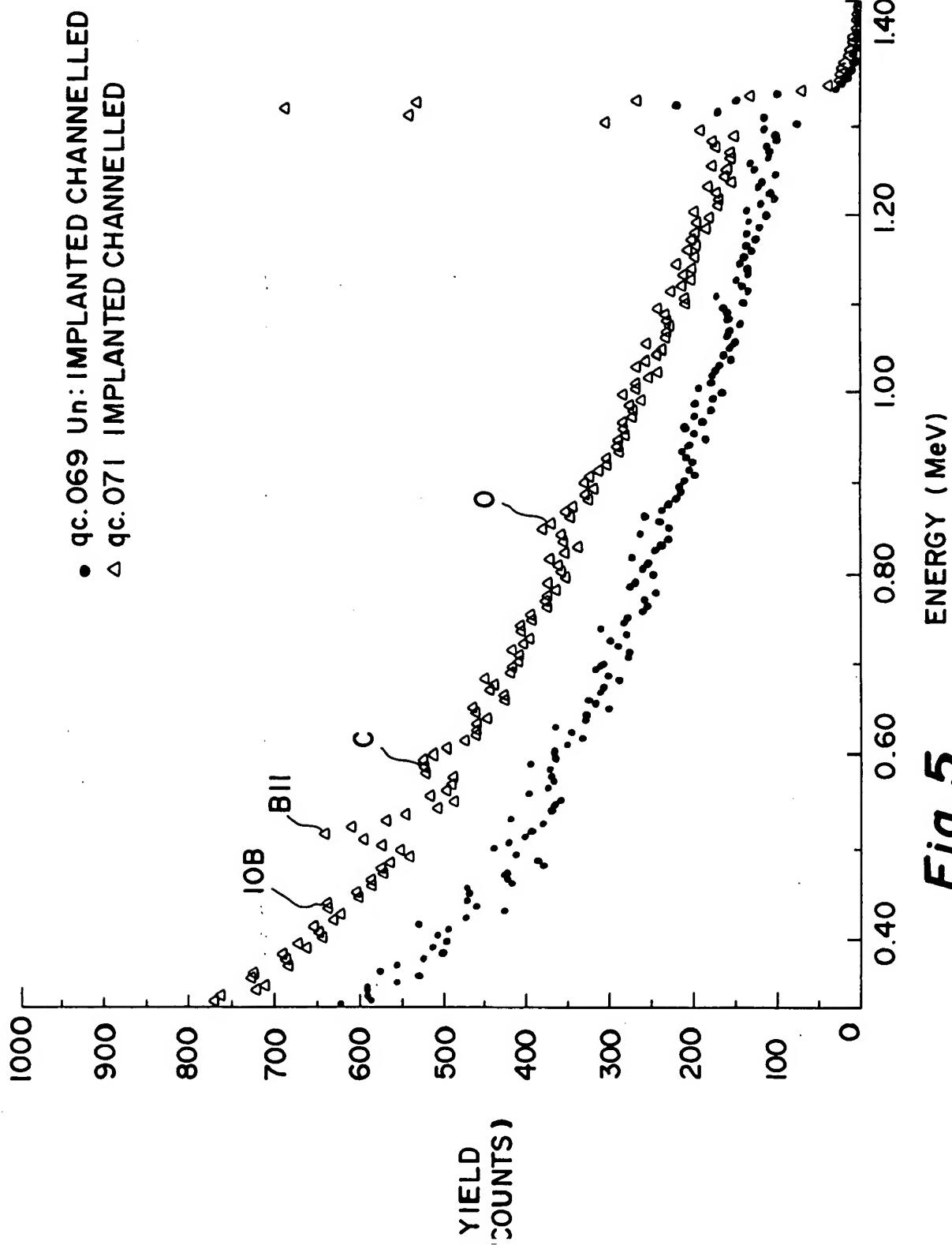


Fig. 5



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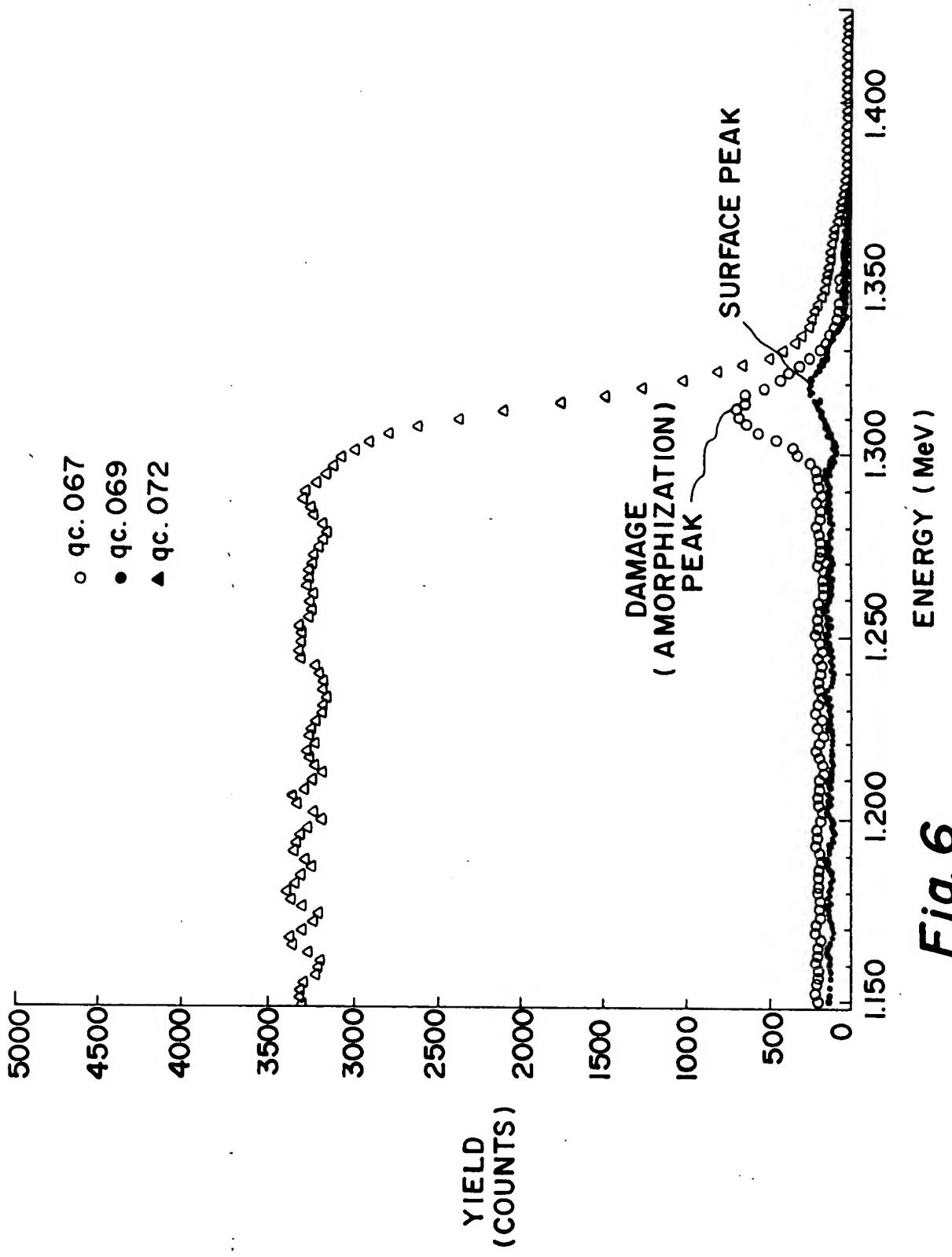
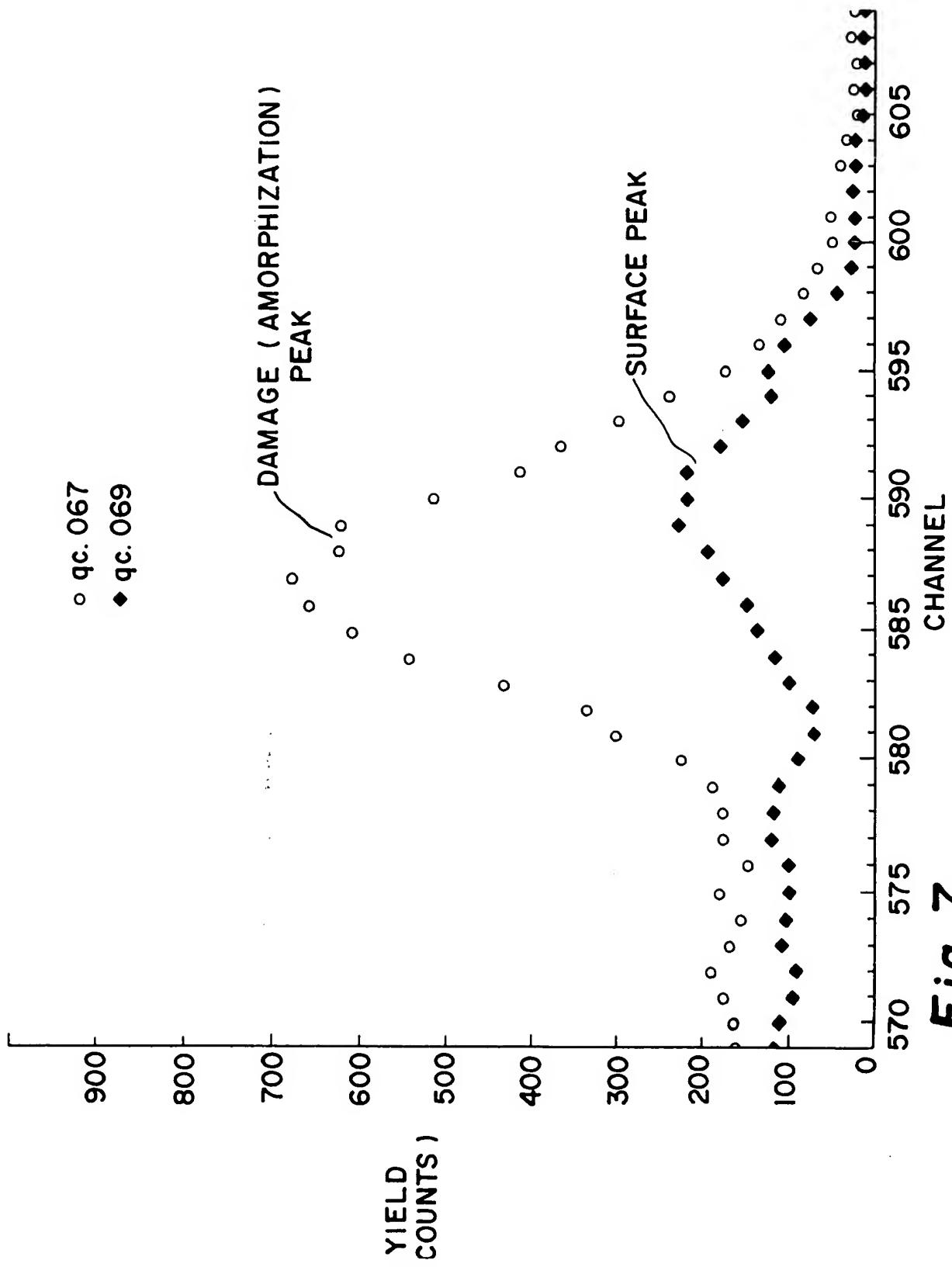


Fig. 6



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qc.072 ROTATING RANDOM (AMORPHOUS) DATA
qsim.072 SIMULATION

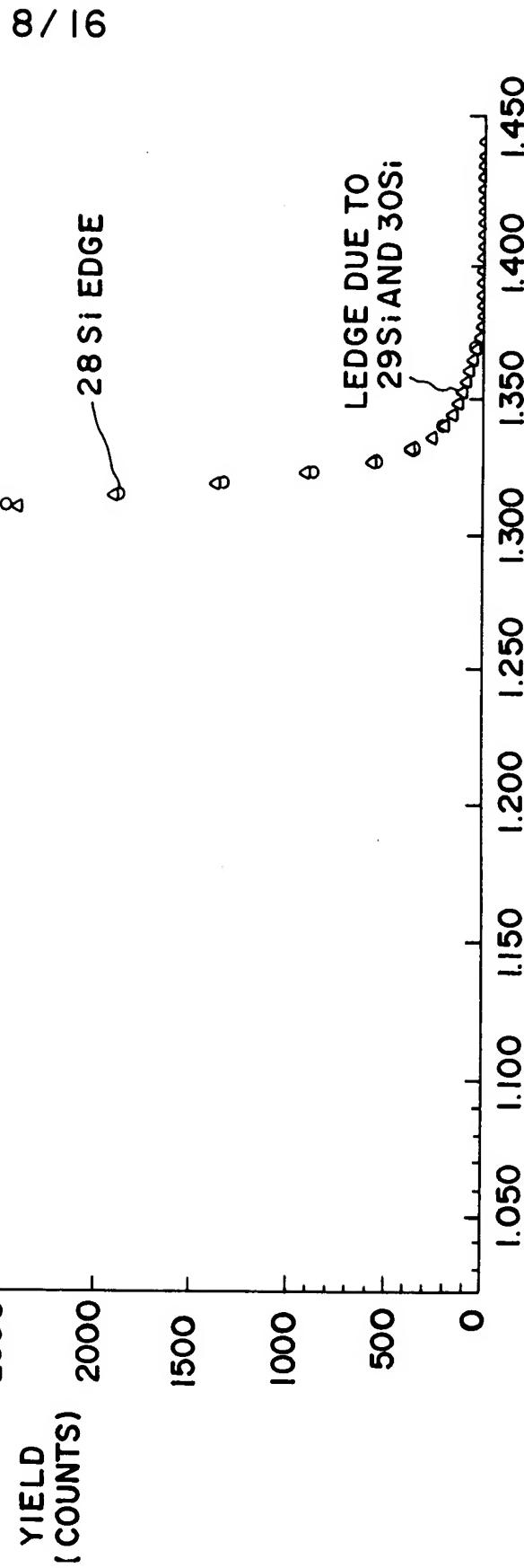


Fig. 8



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qpeak.067- STRIPPED PEAK DATA FROM Fig. 5 qc.
qsim. 067- SIMULATION FOR 92 ANGSTROM
AMORPHOUS Si LAYER USING
PARAMETER DERIVED IN Fig. 6

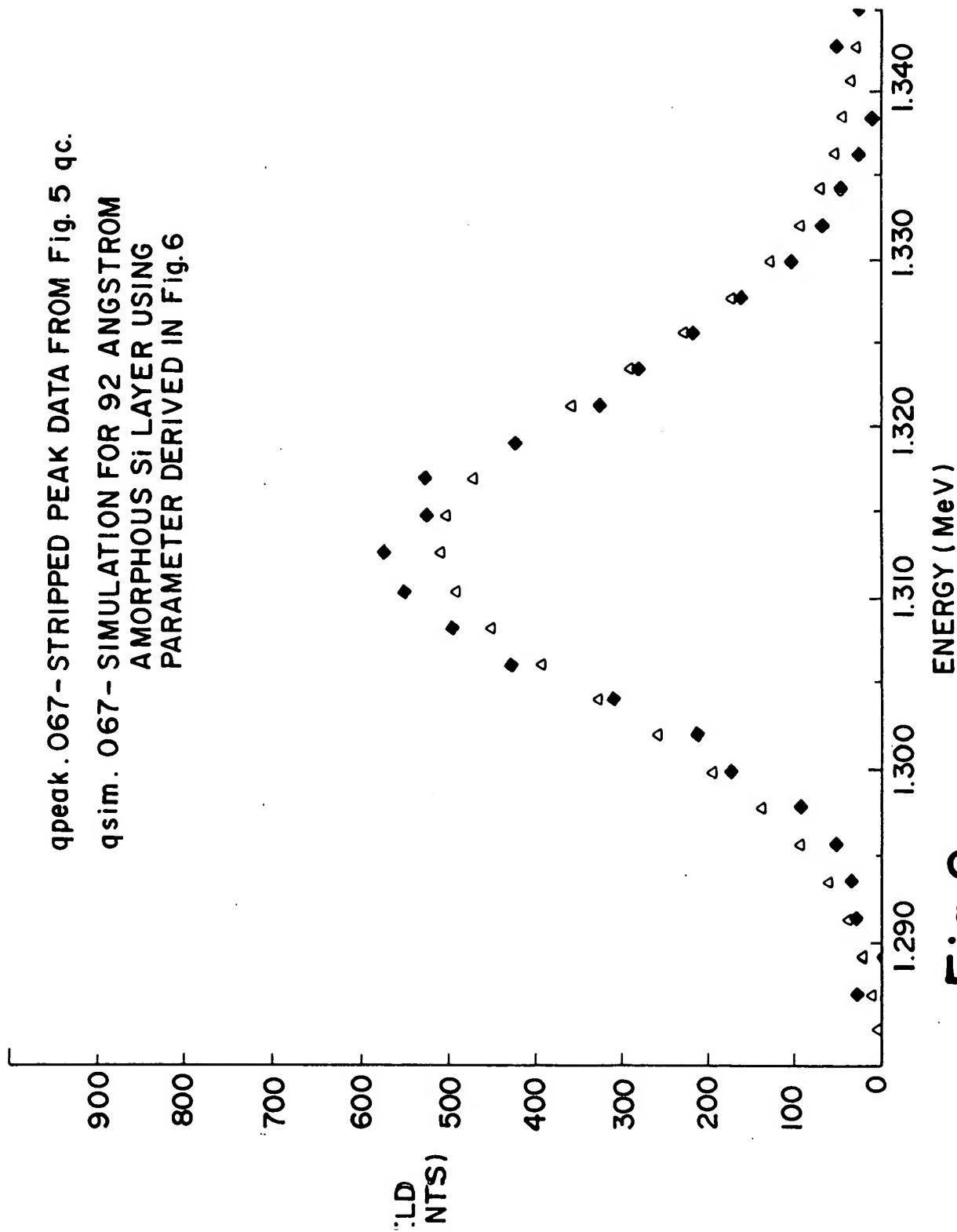


Fig. 9



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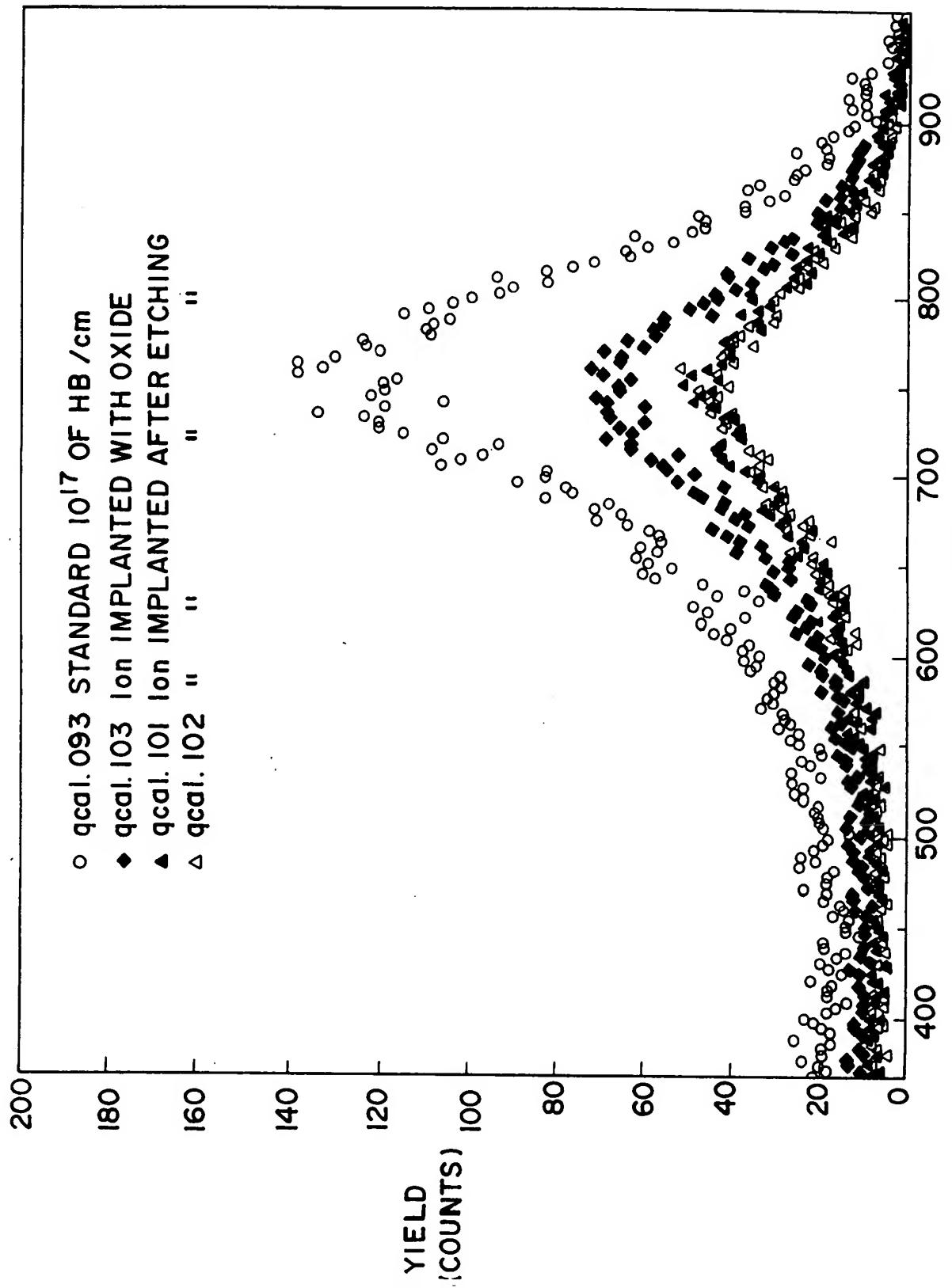


Fig. 10

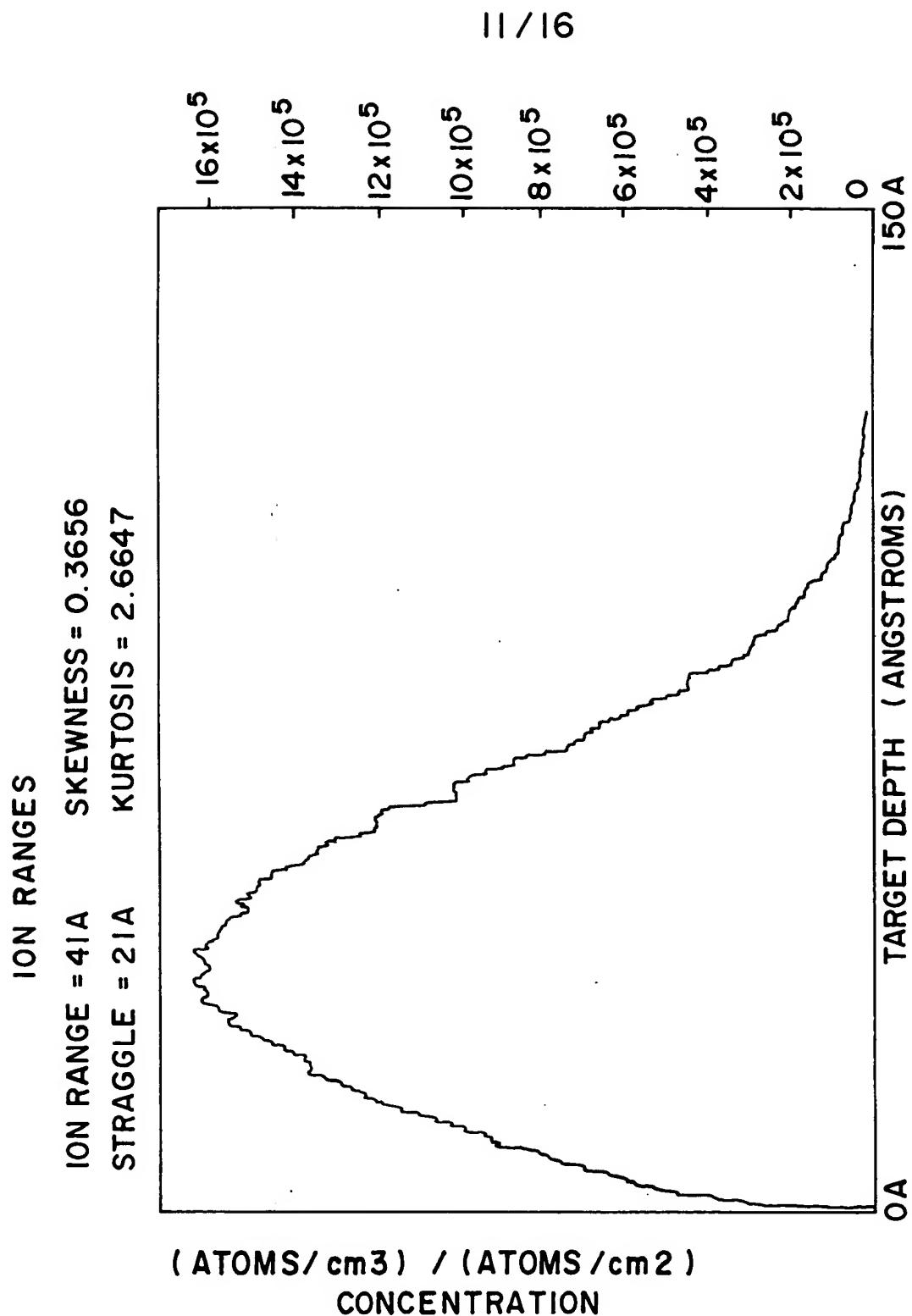


Fig. 11



TARGET = SILICON 2.33G 0° keV Ion Dose/cm ²		keV Ion Dose/cm ²	keV Ion Dose/cm ²
Calc.	Type	Planar, Pearson IV	1
Peak	Data	35Å 1.05e23 67.8%	2
Sput.	Loss	Coef=.000 Tot.=0Å	3
Retn.	Doss	5.84e16/cm ² 97.4%	4
			5
			6
			7
			8
			9
			10

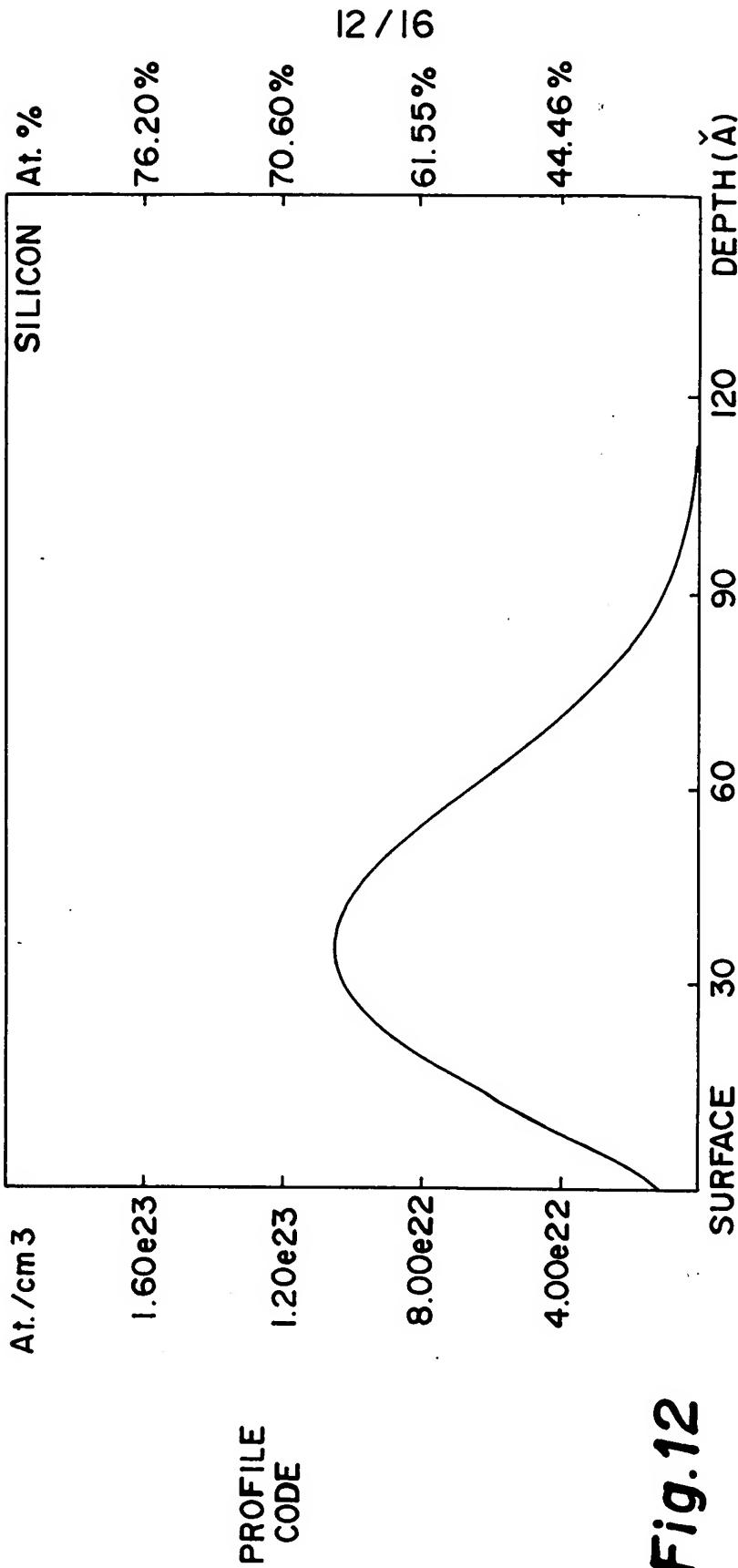
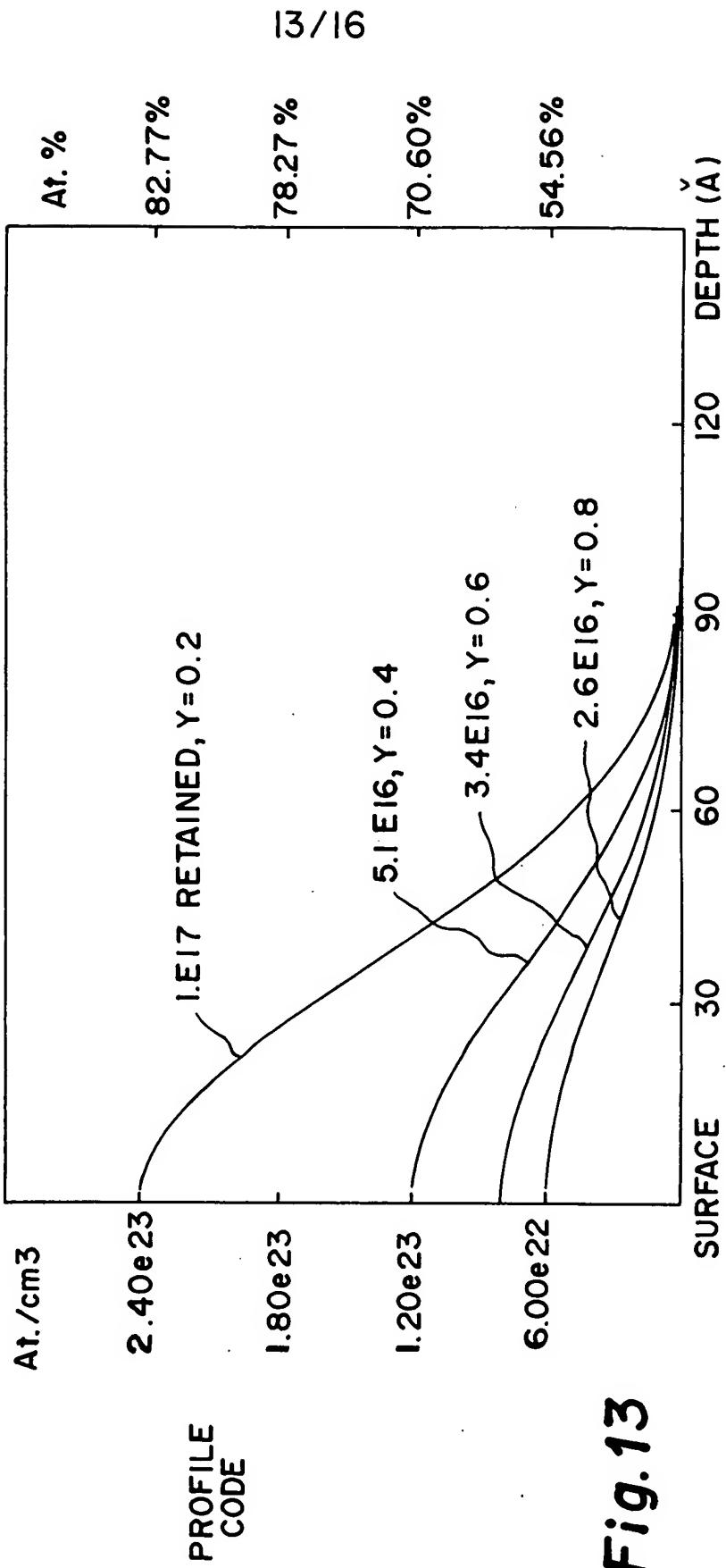


Fig.12



TARGET = SILICON 2.33G		0° keV Ion Dose/cm ²	keV Ion Dose/cm ²
Calc.	Type	Planar, Pearson IV	
Peak	Data	0A 6.07e22	54.9%
Sput.	Loss	Coef.=.800	Tot.=641A
Retn.	Doss	2.56e16/cm ²	6.4%
		5	10





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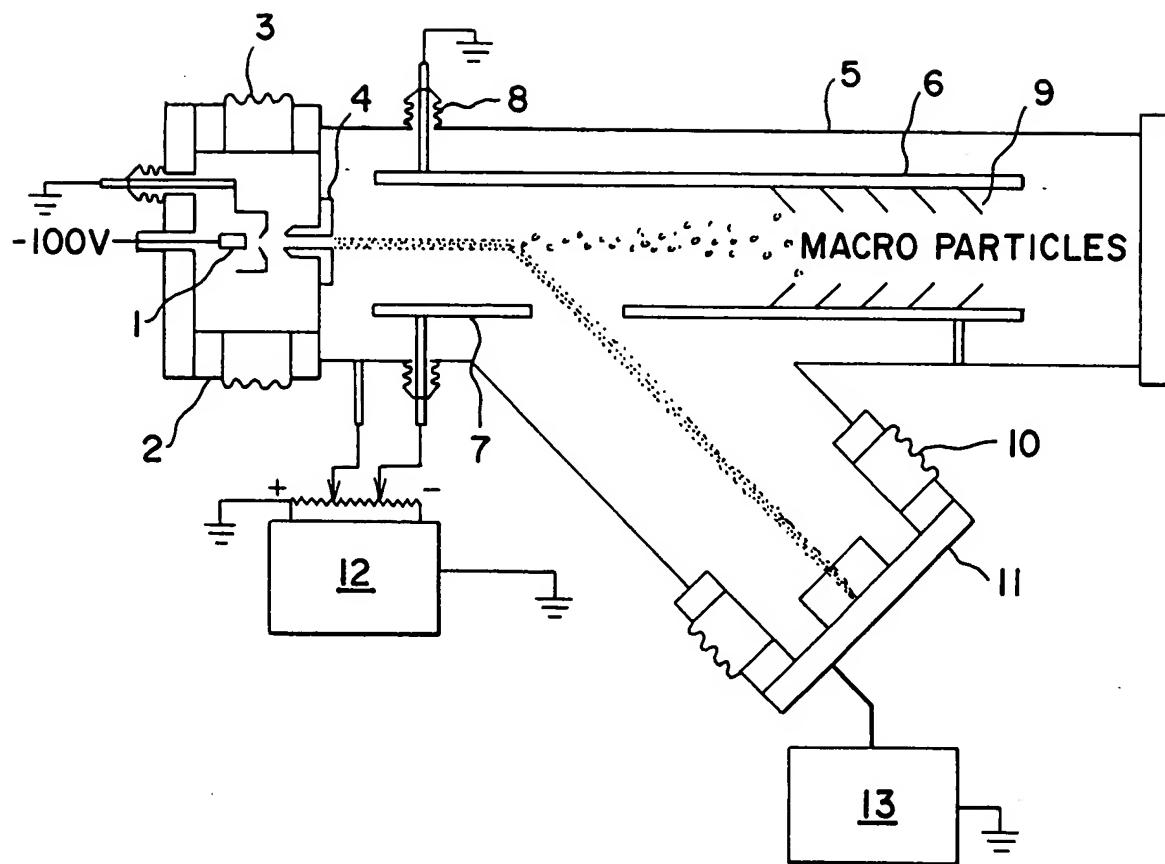


Fig. 14

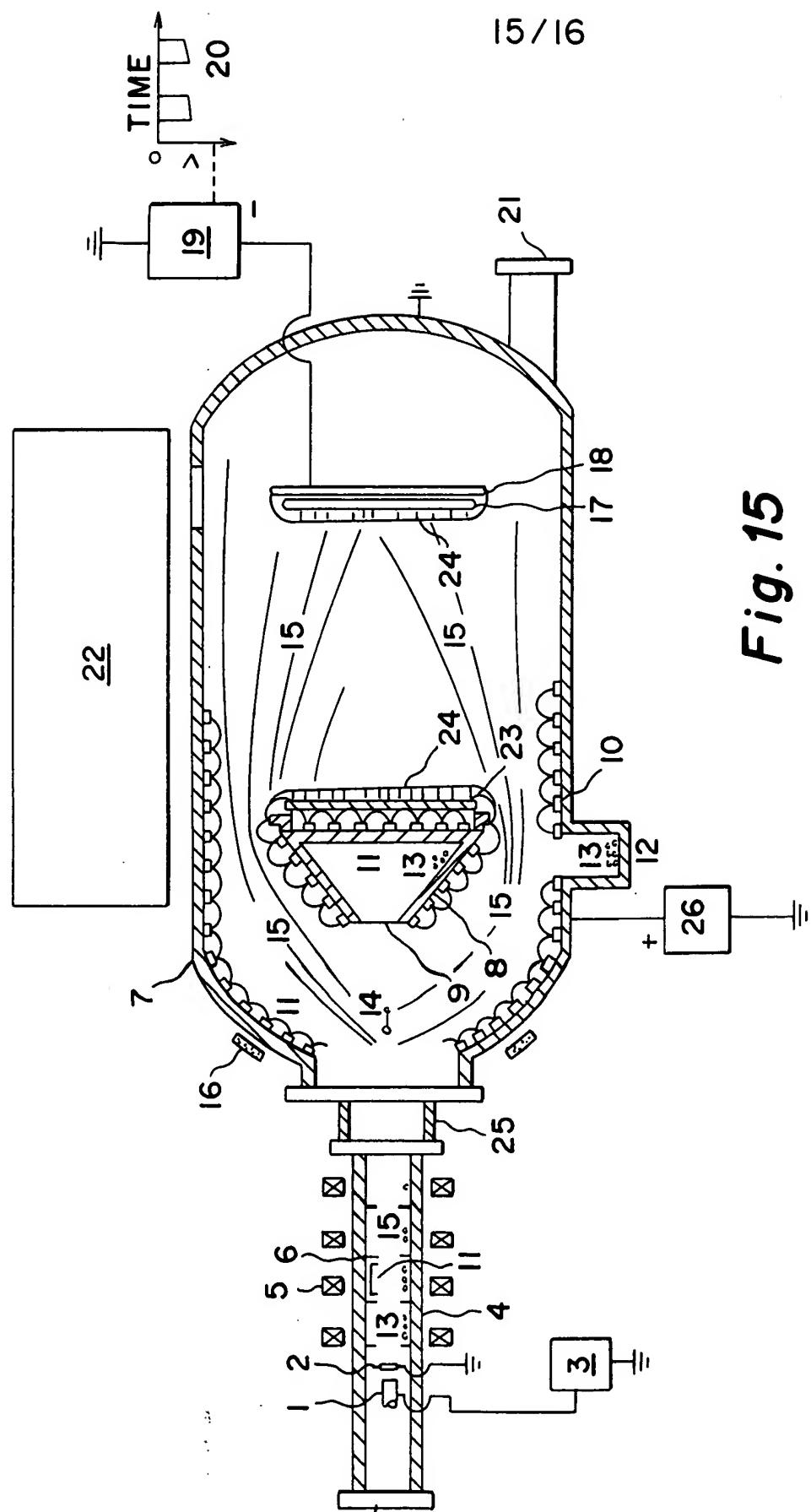


Fig. 15

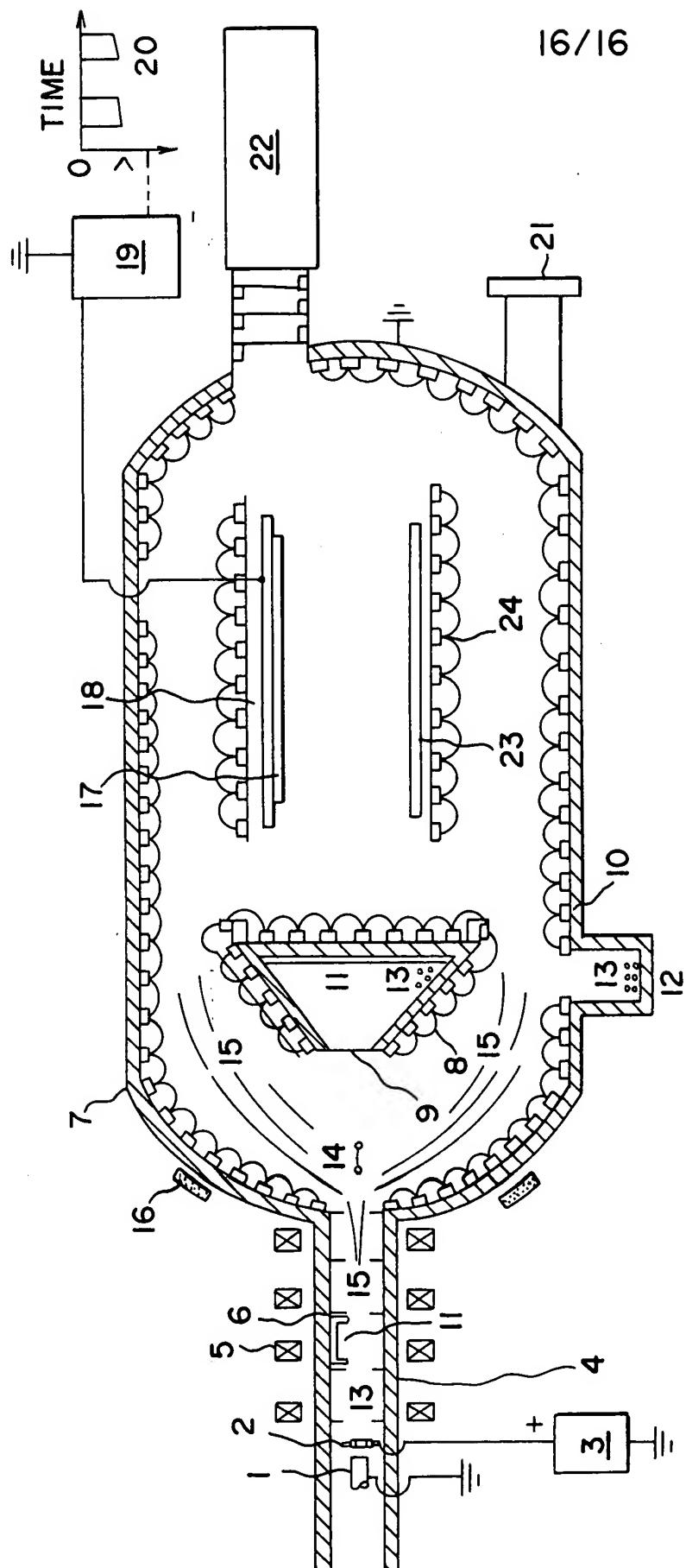


Fig. 16